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TITLE: Phase-noise waveform quality
measuring device e.g. for
analyzing clock signal,
determines instantaneous phase of
signal and removes linear
phase to obtain phase-noise
waveform

PUBN-DATE: October 31, 2001

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JP 3609740 B2		January 12, 2005
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JP 2001337121 A		December 7, 2001
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US 6735538 B1		May 11, 2004
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JP 3609740B2	N/A
2001JP-0091965	March 28, 2001
JP 3609740B2	Previous Publ.
JP2001337121	N/A
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2001DE-1014410	March 23, 2001
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ABSTRACTED-PUB-NO: DE 10114410A

BASIC-ABSTRACT:

NOVELTY - The device includes an analysis signal transformation device for transforming an input signal into a complex analysis signal. An instantaneous phase estimator determines the instantaneous phase of the analysis signal. A linear phase removal device removes the linear phase from the instantaneous phase of the analysis signal to obtain a phase-noise waveform. A quality measurement estimator determines a measure of quality of the phase-noise waveform.

DETAILED DESCRIPTION - An INDEPENDENT CLAIM is included for a method of measuring the quality of a phase-noise waveform.

USE - E.g. for measuring the quality (such as the

amount of jitter) of a clock
signal driving a microprocessor.

ADVANTAGE - Allows measurement of quality of a
phase-noise waveform.

DESCRIPTION OF DRAWING(S) - The drawing is a
diagram representing period
jitter.

CHOSEN-DRAWING: Dwg.1A/10

DERWENT-CLASS: S01 U22

EPI-CODES: S01-D06; U22-D02C;